2004-5 Educational Events
DXC, PPXRD, Workshops

8 March 2005
300 Registrations:
  ◆ 20% from outside of the U.S.A.
  ◆ represented 21 different countries

50 Exhibit Booths Sold
  ◆ over 200 exhibit staff
  ◆ representatives from 41 companies
# Attendance Profile

**21 different countries represented**

<table>
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<tr>
<th>Country</th>
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<tr>
<td>Argentina</td>
<td>Israel</td>
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<td>Australia</td>
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<td>Austria</td>
<td>Japan</td>
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<td>Canada</td>
<td>Korea</td>
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<td>Chile</td>
<td>Norway</td>
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<td>Czech Republic</td>
<td>South Africa</td>
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<td>El Salvador</td>
<td>Sweden</td>
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<td>France</td>
<td>Switzerland</td>
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<td>Germany</td>
<td>United Kingdom</td>
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<td>Hungary</td>
<td>USA</td>
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<td>India</td>
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Awards Presented
Michael Mantler presented the 2004 Birks Award to Tomoya Arai
Jim Kaduk presented the 2004 ICDD Distinguished Fellow Award to Bob Snyder, Georgia Tech
Cam Hubbard presented the 2004 McMurdie Award to Winnie Wong-Ng, NIST
Looking Ahead…
2005 Denver X-ray Conference

• Date: August 1-5
• Location: Sheraton, Colorado Springs
• Plenary Session: X-ray Imaging
  Chaired by Randy Barton and Stuart Stock

Premier event for X-ray analysis scientists, featuring cutting-edge training, applications, techniques, and instrumentation
Technical Program: **14 Workshops**

- X-ray Microtomography
- X-ray Optics
- Rietveld Applications: I—Beginner & II—Advanced
- Stress Analysis
- Line Profile Analysis by the Whole Powder Pattern Fitting
- Two-dimensional X-ray Diffraction
- Specimen Preparation I & II
- Energy Dispersive XRF
- Quantitative XRF I & II
- Basic XRF
- Monte Carlo Techniques in XRF

Pick up your Call for Papers
Technical Program: **16 Special Sessions**

- New Developments in XRD & XRF Instrumentation
- Thin Films
- Detectors & Sources
- Advanced Imaging Techniques
- X-ray Optics
- Microbeam Analysis
- XMT Applied to Materials Characterization
- Stress Analysis
- Industrial Applications of XRD
- Parallel Beam Diffraction
- Line Profile Analysis
- Quantitative XRF
- Problem Solving/Industrial Applications – XRF
- Trace Analysis – ppm to ppb
- Energy Dispersive Applications
- Fusion Applications

Join us!
Future Denver X-ray Conferences

• 2006
  - July 31 - August 4
  - Denver Marriott Tech Center Hotel, Denver, CO

• 2007
  - July 30 – August 3
  - Location TBD
PPXRD-4

Pharmaceutical Powder X-ray Diffraction Symposium

21 - 24 February 2005
Barceló Hotel Sants, Barcelona, Spain
Organizing Committee

- **John Faber**, Chairman, ICDD, PA
- **Detlef Beckers**, PANalytical, The Netherlands
- **Harry Brittain**, Centre for Pharmaceutical Physics, NJ
- **Julien Giovannini**, AstraZeneca, Sweden
- **Jun Han**, Abbott Laboratories, IL
- **Arnt Kern**, Bruker-AXS GmbH, Germany
- **Daniel Louër**, Universite de Rennes I, France
- **Fangling Needham**, ICDD, PA
- **Jordi Rius**, University of Barcelona, Spain
- **Peter Stephens**, SUNY- Stony Brook, NY
- **Greg Stephenson**, Eli Lilly, IN
- **Peter Varlashkin**, GlaxoSmithKline, NC
- **Raj Suryanarayanan**, University of Minnesota, MN
- **Shawn Yin**, Bristol-Myers Squibb, NJ
Symposium Format

**One-day Workshop**
— Indexing Powder Patterns —
&
— Rietveld Structural Refinement —

**2.5 Days of Sessions**

• Formulation, Product Development, Drug Delivery, and Polymorph & Salt Screening
• X-rays in Drug Research
• XRPD Structural Techniques
• Complementary Techniques
• Regulatory & Patent Issues
Stats

• Attendees: 62 representing 20 countries
  – 41 attended symposium only
  – 21 attended symposium + workshop
  – 9 no charge (invited speakers)
  – 8 student registrations

• Exhibits: 5  Exhibitors: 1 (not attending symposium)

• Sponsorships: 2
Countries Represented by Participants

- Austria 1
- Belgium 2
- Czech Republic 1
- Denmark 1
- France 5
- Germany 2
- Iceland 1
- India 2
- Israel 1
- Italy 3
- Korea 1
- The Netherlands 5
- Nigeria 1
- Republic of China, Taiwan 1
- Russia 1
- Spain 8
- Sweden 2
- Switzerland 1
- United Kingdom 10
- USA 13
Manufacturers’ Participation

• Tabletop Exhibits: 6
• Exhibiting Companies: 5
• Dedicated exhibit session on Monday evening, along with the Poster Session & ICDD reception
• PANalytical & XOS sponsored coffee breaks
Invited Speakers

• Eyal Barash, Finnegan, Henderson, Farabow, Garrett, & Dunner, Washington, D.C.
• René Céolin, Univ. Rennes Descartes, Paris, France
• Trevor Cook, Bird & Bird, London, UK
• Bill David, Rutherford Appleton Lab., Oxon, UK
• Christian Lehmann, Max-Planck Inst., Germany
• Franck Leveiller, AstraZeneca, Lund, Sweden
• Daniel Louër, Univ. de Rennes I, Paris, France
• Ken Shankland, Rutherford Appleton Lab., Oxon, UK
• Steve Norval, ICI Measurement Science Group, Redcar, UK
Looking Ahead…

- PPXRD-5 in February 2006
  Philadelphia/ New Jersey corridor

- PPXRD-6 in February 2007
  Barcelona, Spain
Workshops
On-site Clinics

• North Anna Power Station/Dominion
  XRF course held 11-13 May 2004
  – John Anzelmo, program director for our XRF Clinics, was the instructor
  – course evaluations were very positive
The CS department responded to PANalytical’s need to conduct a Pharmaceutical Seminar in the Philadelphia area

- held 21 April 2004, ICDD Headquarters
- attended by approximately 20 PANalytical customers
## Workshops

<table>
<thead>
<tr>
<th>Meeting</th>
<th>Location</th>
<th>Dates</th>
<th>ICDD Rep</th>
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<tbody>
<tr>
<td>BCA Meeting</td>
<td>Manchester, England</td>
<td>6-8 April 2004</td>
<td>Dave Taylor</td>
</tr>
<tr>
<td>DXC</td>
<td>Steamboat Springs, CO</td>
<td>2-6 August 2004</td>
<td>Tim Fawcett, John Faber, Bob Snyder, +</td>
</tr>
<tr>
<td>EPDIC 9</td>
<td>Prague, Czech Republic</td>
<td>2-5 September 2004</td>
<td>John Faber</td>
</tr>
<tr>
<td>SARX</td>
<td>Cordoba, Argentina</td>
<td>25-29 October 2004</td>
<td>Jim Kaduk</td>
</tr>
<tr>
<td>AXAA</td>
<td>Perth, Australia</td>
<td>14-18 February 2005</td>
<td>Jim Kaduk, Brian O'Connor</td>
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Workshops held at the 2004 Denver X-ray Conference

2-6 August 2004, Steamboat Springs, Colorado

• **Rietveld Applications**
  – full-day workshop, given by John Faber and Arnt Kern, Bruker AXS, Inc.

• **Specimen Preparation – XRD**
  – half-day workshop, presented by Tim Fawcett

• **Total Pattern Analysis**
  – half-day workshop, presented by John Faber, Tim Fawcett, and Bob Snyder
2005-2006 Workshops Planned

  - *Rietveld Applications I & II*, another full-day workshop to be given by John Faber and Arnt Kern, Bruker AXS, Inc.

- PANalytical Pharmaceutical Seminar
  - The CS department will again host PANalytical’s Pharmaceutical Seminar at headquarters sometime in April or May 2005.
Historical Clinic Attendance

© 2004
XRD-1 tied for highest attendance record
The 2003 DXC survey said…

Survey reached 910 people, 217 responded

- Issues covered:
  - technical content
  - exhibits
  - administration
  - location
  - hotels
  - general opinion of the conference

Results:
Large majority of respondents are extremely satisfied or satisfied with the existing manner in which the conference is being organized and administered.
More results...

- 57% of attendees were evaluating or purchasing equipment/software

- Suggestions for future workshops & sessions were forwarded to the DXCOC